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15 Q7

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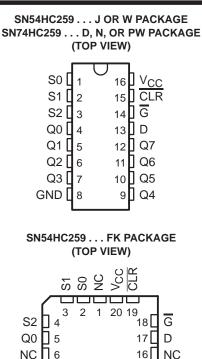
Q6

- 8-Bit Parallel-Out Storage Register Performs Serial-to-Parallel Conversion With Storage
- Asynchronous Parallel Clear
- Active-High Decoder
- Enable Input Simplifies Expansion
- Expandable for n-Bit Applications
- Four Distinct Functional Modes
- Package Options Include Plastic Small-Outline (D), Thin Shrink Small-Outline (PW), and Ceramic Flat (W) Packages, Ceramic Chip Carriers (FK), and Standard Plastic (N) and Ceramic (J) 300-mil DIPs

description

These 8-bit addressable latches are designed for general-purpose storage applications in digital systems. Specific uses include working registers, serial-holding registers, and active-high decoders or demultiplexers. They are multifunctional devices capable of storing single-line data in eight addressable latches, and being a 1-of-8 decoder or demultiplexer with active-high outputs.

Four distinct modes of operation are selectable by controlling the clear (\overline{CLR}) and enable (\overline{G}) inputs. In the addressable-latch mode, data at the data-in terminal is written into the addressed latch. The addressed latch follows the data input with all unaddressed latches remaining in their previous states. In the memory mode, all latches remain in their previous states and are unaffected by the data or address inputs. To eliminate the possibility of entering erroneous data in the latches, \overline{G} should be held high (inactive) while the address lines are changing. In the 1-of-8 decoding or demultiplexing mode, the addressed output follows the level of the D input with all other outputs low. In the clear mode, all outputs are low and unaffected by the address and data inputs.



9 10 11 12 13

80 80 80

GND GND

NC - No internal connection

Q1 🛛 7

Q2 | 8

and unaffected by the address and data inputs. The SN54HC259 is characterized for operation over the full military temperature range of –55°C to 125°C. The SN74HC259 is characterized for operation from –40°C to 85°C.



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.



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Function Tables

	FUNCTION											
INPU	JTS	OUTPUT OF	EACH OTHER	FUNCTION								
CLR	G	LATCH	OUTPUT	FUNCTION								
н	L	D	Q _{iO}	Addressable latch								
н	Н	Q _{iO}	Q _{iO}	Memory								
L	L	D	L	8-line demultiplexer								
L	Н	L	L	Clear								

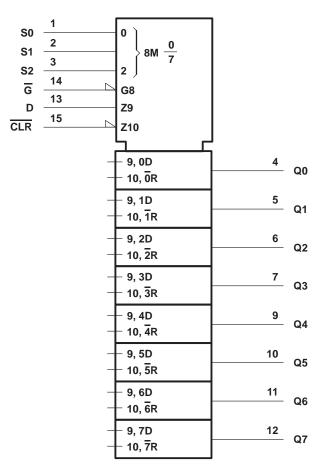
LATCH SELECTION

SEL	ECT INP	UTS	LATCH
S2	S 1	S0	ADDRESSED
L	L	L	0
L	L	Н	1
L	Н	L	2
L	Н	Н	3
н	L	L	4
н	L	Н	5
н	Н	L	6
н	Н	Н	7



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logic symbol[†]

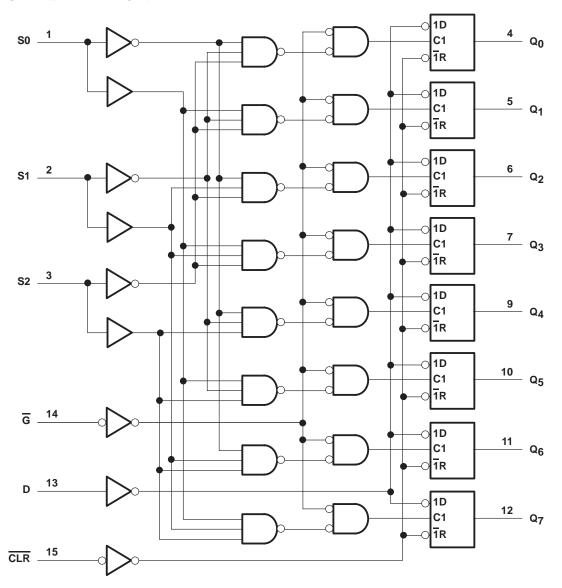


[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12. Pin numbers shown are for the D, J, N, PW, and W packages.



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logic diagram (positive logic)



Pin numbers shown are for the D, J, N, PW, and W packages.

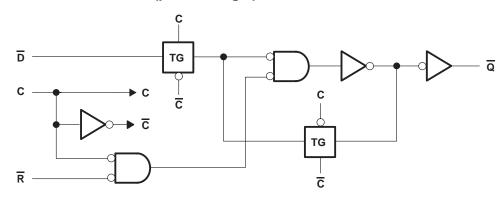


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logic symbol, each internal latch



logic diagram, each internal latch (positive logic)



absolute maximum ratings over operating free-air temperature range[†]

Supply voltage range, V_{CC} Input clamp current, I_{IK} (VI < 0 or VI > V _{CC}) (see		
Output clamp current, I_{OK} (V _O < 0 or V _O > V _{CC}		
Continuous output current, $I_O (V_O = 0 \text{ to } V_{CC})$		±25 mA
Continuous current through V _{CC} or GND		±50 mA
Package thermal impedance, θ_{JA} (see Note 2):	D package	113°C/W
	N package	
	PW package	149°C/W
Storage temperature range, T _{stg}		–65°C to 150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

2. The package thermal impedance is calculated in accordance with JESD 51, except for through-hole packages, which use a trace length of zero.



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recommended operating conditions

			SN	SN54HC259			SN74HC259		
			MIN	NOM	MAX	MIN	NOM	MAX	UNIT
VCC	Supply voltage		2	5	6	2	5	6	V
		$V_{CC} = 2 V$	1.5			1.5			
VIH	High-level input voltage	$V_{CC} = 4.5 V$	3.15			3.15			V
		$V_{CC} = 6 V$	4.2			4.2			
		$V_{CC} = 2 V$	0		0.5	0		0.5	
VIL	Low-level input voltage	$V_{CC} = 4.5 V$	0		1.35	0		1.35	V
		$V_{CC} = 6 V$	0		1.8	0		1.8	
VI	Input voltage		0		VCC	0		VCC	V
Vo	Output voltage		0		VCC	0		VCC	V
		$V_{CC} = 2 V$	0		1000	0		1000	
tt	Input transition (rise and fall) time	$V_{CC} = 4.5 V$	0		500	0		500	ns
		V _{CC} = 6 V	0		400	0		400	
ТА	Operating free-air temperature		-55		125	-40		85	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS		N	Т	A = 25°C	;	SN54HC259		SN74HC259		UNIT
PARAMETER	TEST CC	INDITIONS	Vcc	MIN	TYP	MAX	MIN	MAX	MIN	HC259 MAX 0.1 0.1 0.33 0.33 ±1000 80	UNIT
			2 V	1.9	1.998		1.9		1.9		
		I _{OH} = -20 μA	4.5 V	4.4	4.499		4.4		4.4		
VOH	$V_I = V_{IH} \text{ or } V_{IL}$		6 V	5.9	5.999		5.9		5.9		V
		I _{OH} = -4 mA	4.5 V	3.98	4.3		3.7		3.84		
		I _{OH} = -5.2 mA	6 V	5.48	5.8		5.2		5.34		
		I _{OL} = 20 μA	2 V		0.002	0.1		0.1		0.1	
	VI = VIH or VIL		4.5 V		0.001	0.1		0.1		0.1	
VOL			6 V		0.001	0.1		0.1		0.1	V
		I _{OL} = 4 mA	4.5 V		0.17	0.26		0.4		0.33	
		I _{OL} = 5.2 mA	6 V		0.15	0.26		0.4		0.33	
l	$V_{I} = V_{CC} \text{ or } 0$		6 V		±0.1	±100		±1000		±1000	nA
ICC	$V_{I} = V_{CC} \text{ or } 0,$	I <mark>O</mark> = 0	6 V			8		160		80	μΑ
Ci			2 V to 6 V		3	10		10		10	pF



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timing requirements over recommended operating free-air temperature range (unless otherwise noted)

			N	T _A = 2	25°C	SN54F	IC259	SN74F	IC259	UNIT
			Vcc	MIN	MAX	MIN	MAX	MIN	MAX	UNIT
			2 V	80		120		100		
		CLR low	4.5 V	16		24		20		
.	Pulse duration		6 V	14		20		17		20
tw			2 V	80		120		100		ns
		G low	4.5 V	16		24		20		
			6 V	14		20		17		
			2 V	75		115		95		
t _{su}	Setup time, data or address before $\overline{G} \! \uparrow$		4.5 V	15		23		19		ns
			6 V	13		20		16		
			2 V	5		5		5		
th	Hold time, data or address after \overline{G}^{\uparrow}		4.5 V	5		5		5		ns
			6 V	5		5		5		

switching characteristics over recommended operating free-air temperature range, $C_L = 50 \text{ pF}$ (unless otherwise noted) (see Figure 1)

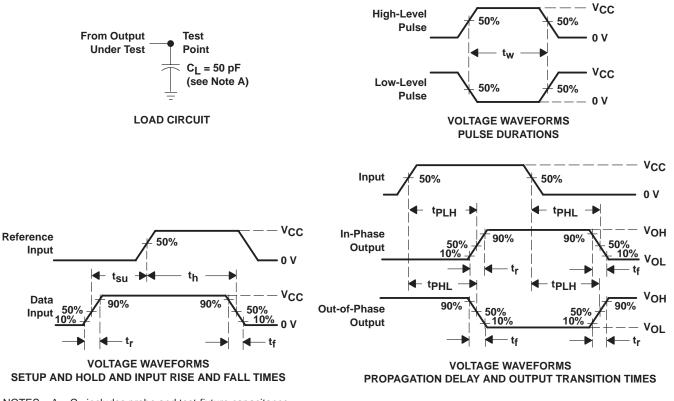
PARAMETER	FROM	то	Vee	٦T	∖ = 25°C	;	SN54H	IC259	SN74H	C259	
FARAMETER	(INPUT)	(OUTPUT)	Vcc	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT
			2 V		60	150		225		190	
^t PHL	CLR	Any Q	4.5 V		18	30		45		38	ns
			6 V		14	26		MAX MIN MAX UNIT 225 190			
			2 V		56	130		195		165	
	Data	Any Q	4.5 V		17	26		39		33	
			6 V		13	22		33		28	
			2 V		74	200		300		250	
^t pd	Address	Any Q	4.5 V		21	40		60	50	ns	
			6 V		17	34		51		43	
	G	Any Q	2 V		66	170		255		215	
			4.5 V		20	34		51		43	
			6 V		16	29		43		37	
			2 V		28	75		110		95	
tt		Any	4.5 V		8	15		22		19	ns
			6 V		6	13		19		16	

operating characteristics, $T_A = 25^{\circ}C$

	PARAMETER	TEST CONDITIONS	TYP	UNIT
Cpd	Power dissipation capacitance per latch	No load	33	рF



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PARAMETER MEASUREMENT INFORMATION

NOTES: A. CL includes probe and test-fixture capacitance.

- B. Phase relationships between waveforms were chosen arbitrarily. All input pulses are supplied by generators having the following characteristics: PRR \leq 1 MHz, Z_O = 50 Ω , t_f = 6 ns, t_f = 6 ns.
- C. The outputs are measured one at a time with one input transition per measurement.
- D. tpLH and tpHL are the same as tpd.

Figure 1. Load Circuit and Voltage Waveforms



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